

Search Notes

Application No.

09/786,680

Examiner

Cheukfan Lee

Applicant(s)

ONISHI ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
358	482,483, 512-514	2/16/2005	C.L.
	475,474		
	497,496		
	494,473		
	487,505		
	234-236		
	484, 509		
382	312,313		
	318,319		
250	208.1		
	234-236		
399	211		
359	209-212		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
358	475,482	2/17/2005	C.L.
	483		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search: (CIS (contact adj2 image adj sensor)), (scanning adj module), (scan\$5 head), (partition, divider)	2/16/2005	C.L.
EAST search (cont.): (light adj guid\$3), (optical adj2 guide)		
Intense Image search		